


<b>Search Notes</b>  	<b>Application/Control No.</b>  10541252	<b>Applicant(s)/Patent Under Reexamination</b>  LEE, JONGHUN
	<b>Examiner</b>  SAYED T ZEWAR	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
455	436-444, 426.1-426.2, 552.1, 553.1, 434, 452.2, 560-562,	3/13/2008	STZ
370	331-337, 352-354, 328, 355, 342	3/14/2008	STZ
455, 370	text search. Please see the search history	3/13/2008	STZ

SEARCH NOTES			
Search Notes	Date	Examiner	
bout this case with Charles Appiah, Dun Nygun, Bill Trost, and Melanies Jagannathac	3/13/2008	STZ	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	Please see the interference search history	3/14/2008	STZ